

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Dinesh ChopraPriority FILING DATE
March 3, 2000

Priority GROUP 2822

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
TYT	AA	4,393,096	7/83	Gajda	—	—	—
	AB	5,071,714	12/91	Rodbell et al	—	—	—
	AC	5,565,378	10/96	Harada et al	—	—	—
	AD	5,656,860	8/97	Lee	—	—	—
	AE	6,030,895	2/00	Joshi et al	—	—	—
	AF	6,110,819	8/00	Colgan et al	—	—	—
	AG	6,110,829	8/00	Besser et al	—	—	—
	AH	6,140,236	10/00	Restaino et al	—	—	—
	AJ	6,146,988	11/00	Ngo et al	—	—	—
	AJ	6,147,000	11/00	You et al	—	—	—
	AK	6,171,960 B1	1/01	Lee	—	—	—
	AL	6,174,810 B1	1/01	Islam et al	—	—	—

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
TYT	AM	JP 404280979A	10/92	Japan	—	—		
	AN							
	AO							
	AP							
	AQ							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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TYT	AA	6,214,731 B1	4/01	Nogami et al	—	—	—
	AB	6,147,000	11/00	You et al	—	—	—
	AC	6,107,687	08/00	Fukada et al	—	—	—
	AD	5,592,024	01/97	Aoyama et al	1	1	—
	AE	5,455,195	10/95	Ramsey et al	1	1	—
	AF	5,518,936	5/96	Yamamoto et al	1	—	—
	AG	6,261,939	7/01	Skalai et al	—	1	—
	AH	6,261,950	7/01	Tobben et al	—	1	—
	AI	6,306,750	10/01	Huang et al	—	1	—
	AJ	6,329,722	12/01	Shih et al	—	1	—
	AK	6,358,849	03/02	Havemann et al	—	1	—
	AL	6,323,131	11/01	Obeng et al	—	1	—

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U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
TYT	AA	5,898,222	4/99	Farooq et al	—	—	—
	AB	5,360,995	11/94	Graas	—	—	—
	AC	5,378,660	01/95	Ngan et al	—	—	—
	AD	5,547,881	08/96	Wang et al	—	—	—
	AE	5,656,546	08/97	Chen	—	—	—
	AF	5,851,922	12/98	Bovk et al	—	—	—
	AG	5,885,896	03/99	Thakur et al	—	—	—
	AH	6,468,906	10/02	Chan et al	—	—	—
	AI	3,826,886	07/74	Hara et al	—	—	—
	AJ	3,839,727	10/74	Hordzik et al	—	—	—
	AK	3,839,780	10/74	Freedman et al	—	—	—
	AL	3,887,994	06/75	Ku et al	—	—	—

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TYT	AA	4,319,967	03/82	Vratny et al	—	—	—
	AB	4,565,586	01/86	Church et al	—	—	—
	AC	4,698,233	10/87	Ohira et al	—	—	—
	AD	5,096,508	03/92	Breedis et al	—	—	—
	AE	5,258,329	11/93	Shibata	—	—	—
	AF	5,272,015	12/93	Hamdi et al	—	—	—
	AG	5,296,653	03/94	Kiyota et al	—	—	—
	AH	5,390,141	02/95	Cohen et al	—	—	—
	AI	5,788,830	08/98	Sakamoto et al	—	—	—
	AJ	6,100,195	08/00	Chan et al	—	—	—
	AK	6,171,949	01/01	You et al	—	—	—
	AL	6,174,812	01/01	Hsiung et al	—	—	—
	AM	6,644,567	09/02	Besser et al	—	—	—
	AN	6,468,906	10/02	Chan et al	—	—	—
	AO	6,495,200	12/02	Chan et al	—	—	—
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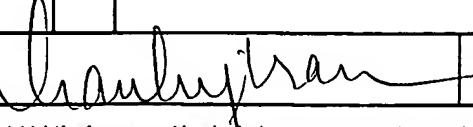
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				FILING DATE July 15, 2003	GROUP 2822		
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass		
TYT	AA 5,700,735	12/1997	Shiu et al	—	—		
	AB						
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